

Notice of References Cited

Application/Control No.

10/609,468

Applicant(s)/Patent Under
Reexamination
KODATE ET AL.

Examiner

Jeff Piziali

Art Unit

2629

Page 1 of 3

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-4,457,589 A	07-1984	Tamura et al.	349/142
*	B	US-4,904,056 A	02-1990	Castleberry, Donald E.	349/162
*	C	US-5,150,239 A	09-1992	Watanabe et al.	349/153
*	D	US-5,396,350 A	03-1995	Beeson et al.	349/62
*	E	US-5,497,258 A	03-1996	Ju et al.	349/58
*	F	US-5,739,882 A	04-1998	Shimizu et al.	349/123
*	G	US-5,917,572 A	06-1999	Kurauchi et al.	349/156
*	H	US-5,969,784 A	10-1999	Miyazaki et al.	349/155
*	I	US-5,978,061 A	11-1999	Miyazaki et al.	349/155
*	J	US-6,147,729 A	11-2000	Kurauchi et al.	349/106
*	K	US-2001/0017677 A1	08-2001	Kishimoto et al.	349/106
*	L	US-6,323,921 B1	11-2001	Kurauchi et al.	349/106
*	M	US-2001/0040665 A1	11-2001	Ahn, Byung Chul	349/156

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)				
	U					
	V					
	W					
	X					

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
 Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

Notice of References Cited

Application/Control No.

10/609,468

Applicant(s)/Patent Under
Reexamination
KODATE ET AL.

Examiner

Jeff Piziali

Art Unit

2629

Page 2 of 3

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2001/0052960 A1	12-2001	Saito et al.	349/155
*	B	US-2002/0008813 A1	01-2002	Miyakawa et al.	349/106
*	C	US-2002/0005846 A1	01-2002	Hiroki et al.	345/204
*	D	US-2002/0033912 A1	03-2002	Tanaka et al.	349/106
*	E	US-2002/0075442 A1	06-2002	Yanagawa et al.	349/155
*	F	US-2002/0075438 A1	06-2002	Takase, Takeshi	349/149
*	G	US-2002/0067451 A1	06-2002	Hattori et al.	349/129
*	H	US-2002/0089615 A1	07-2002	Sakamoto et al.	349/43
*	I	US-2002/0101414 A1	08-2002	Lifka et al.	345/205
*	J	US-2002/0113935 A1	08-2002	Yanagawa et al.	349/155
*	K	US-6,433,852 B1	08-2002	Sonoda et al.	349/156
*	L	US-6,445,437 B1	09-2002	Miyazaki et al.	349/156
*	M	US-6,486,930 B1	11-2002	Kwon, Oh-kyong	349/48

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

Notice of References Cited

Application/Control No.

10/609,468

Applicant(s)/Patent Under
Reexamination
KODATE ET AL.

Examiner

Jeff Piziali

Art Unit

2629

Page 3 of 3

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2002/0163615 A1	11-2002	Fujioka et al.	349/154
*	B	US-6,515,720 B1	02-2003	Iizuka et al.	349/39
*	C	US-6,549,260 B1	04-2003	Shibahara, Hideo	349/155
*	D	US-6,583,846 B1	06-2003	Yanagawa et al.	349/155
*	E	US-2003/0128309 A1	07-2003	Yamada, Tsutomu	349/106
*	F	US-6,683,671 B1	01-2004	Morimoto, Hirokazu	349/155
*	G	US-6,762,818 B2	07-2004	Yamada, Tsutomu	349/155
*	H	US-6,774,975 B2	08-2004	Ahn, Byung Chul	349/156
*	I	US-7,095,460 B2	08-2006	Choi et al.	349/43
*	J	US-7,274,424 B1	09-2007	Kurihara et al.	349/155
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.